

Search Notes

Application/Control No.

10/725,139

Examiner

Elias Desta

Applicant(s)/Patent under
Reexamination

SATO ET AL.

Art Unit

2857

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|---------------------|-----------|----------|
| 702 | 182,183,1 89,190 | 7/20/2006 | E.D |
| 118 | 723e | 7/20/2006 | E.D |
| 156 | 345.24 | 7/20/2006 | E.D |
| | 345.25 | | |
| 216 | 59-61, 67 | 7/20/2006 | E.D |
| | 72-58 | | |
| 438 | 738-751 | 7/20/2006 | E.D |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|--|-----------|------|
| Method of search: EAST, GOOGLE, YAHOO, IEEE Explore, CRC and Semiconductor Process Text book | 7/20/2006 | E.D |
| Consulted: Tod Swann, 101 panel; Hassanzader Parviz, class 216, au: 1763 | 1/31/2006 | E.D |
| Text or key word searches: see attachments | 7/20/2006 | E.D |
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